

Deformation Mechanisms of Geological Materials at the Nanoscale

C. Chisholm, W.M. Mook, A.G. Ilgen, K.L. Jungjohann
Sandia National Laboratories, Albuquerque, NM 87185, USA



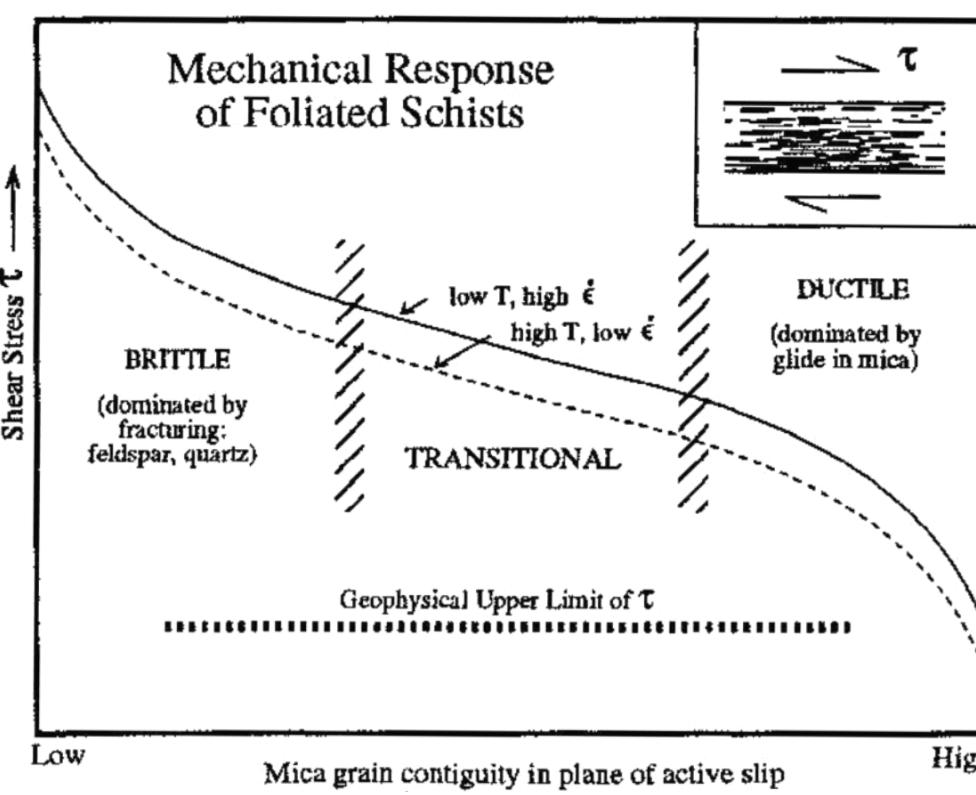
Predicting Materials Behavior: Observations Across Length Scales

- A fundamental understanding of the deformation mechanisms of geological materials is critical when considering designs that require predictive mechanical behavior of geological materials
 - ex. Geological storage of CO₂, nuclear waste storage, geothermal heat pumps, and hydraulic fracturing
- Mica minerals
 - are abundant, comprising almost 15% of the upper continental crust^[1]
 - have a layered sheet-like structure
 - shear along the basal plane with relative ease
 - greatly influence the mechanical properties of its host rock^[2]
- Ex-situ^[3] and qualitative in-situ^[4] Transmission Electron Microscopy (TEM) straining experiments of mica have so far observed
 - strength is a function of shear stress and loading direction
 - dislocation glide is confined to the basal plane
 - Orowan dislocation bowing mechanism

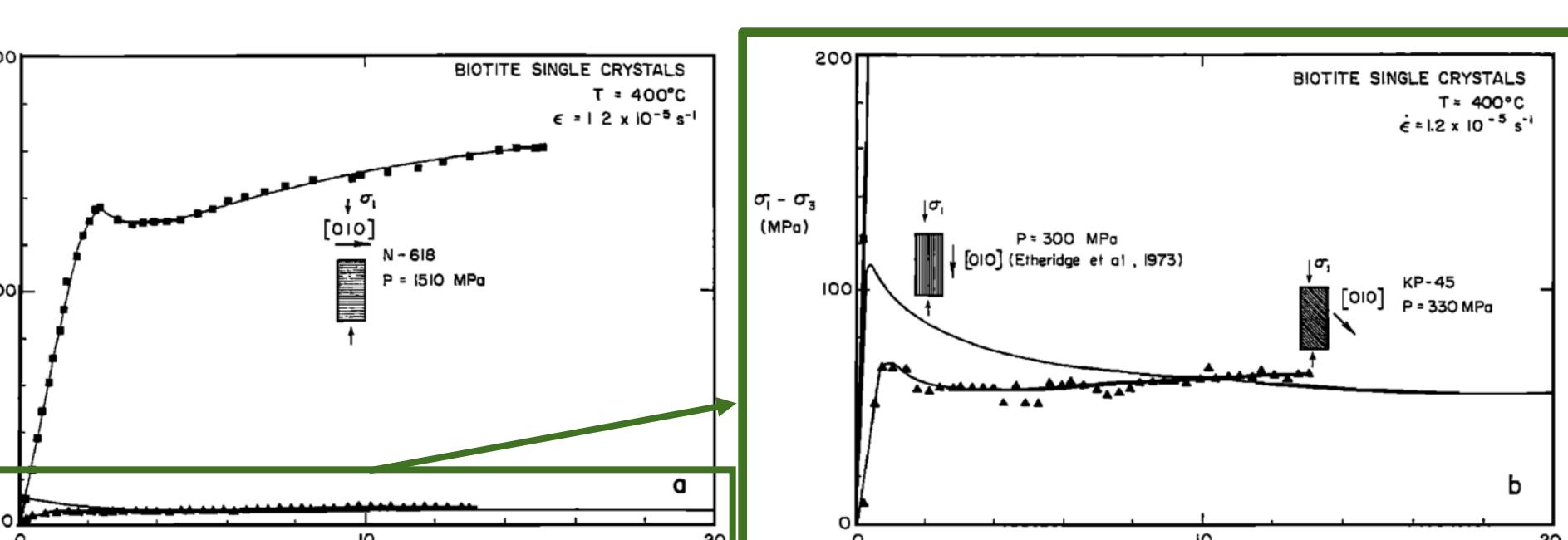
By quantitatively investigating deformation and fracture in mica minerals at the nanoscale, this research aims to generate a fundamental understanding of geological mechanical behavior by

- establishing deformation mechanisms in mica as a function of shear stress and loading direction
- quantitatively measuring activation and interaction energies of participating defects in mica

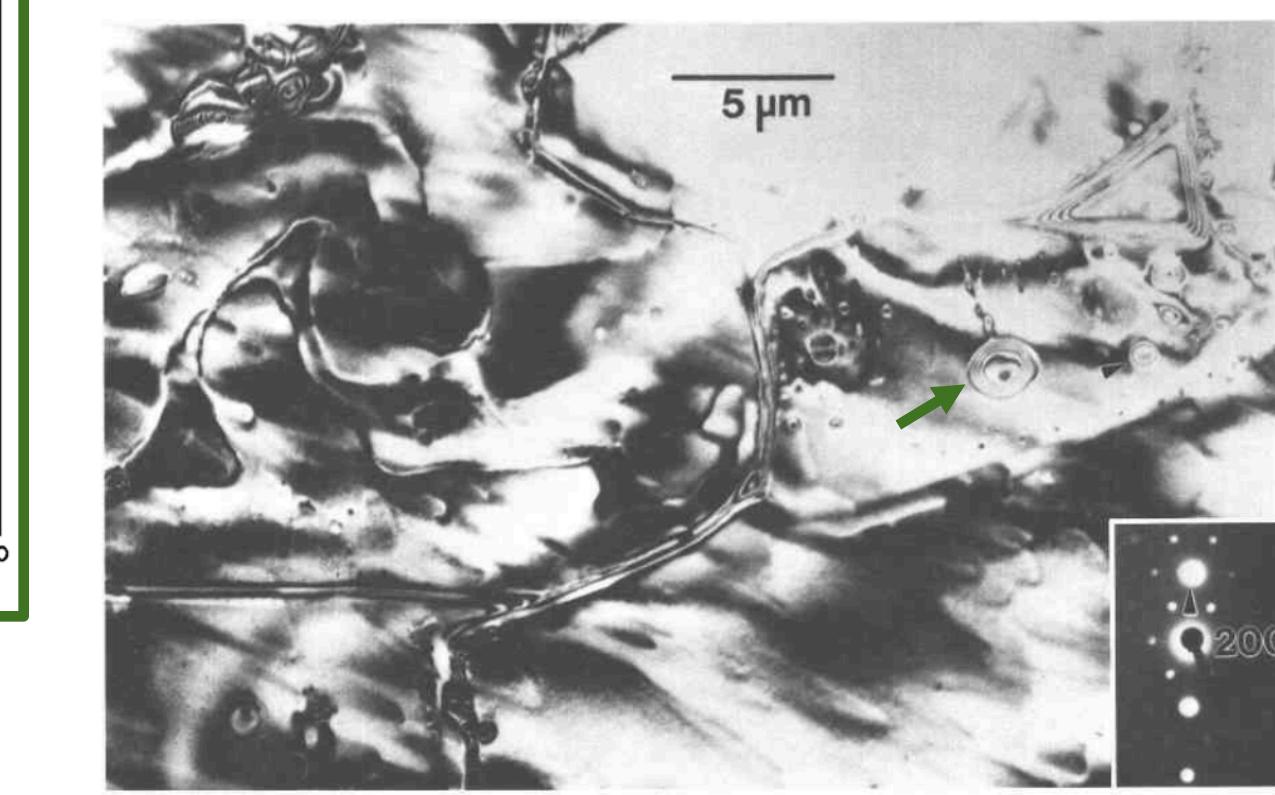
Constituent materials control the overall strength of rock^[2]



Strength of mica is function of shear stress and loading direction^[3]



Dislocation glide confined to mica basal plane, Orowan mechanism^[4]



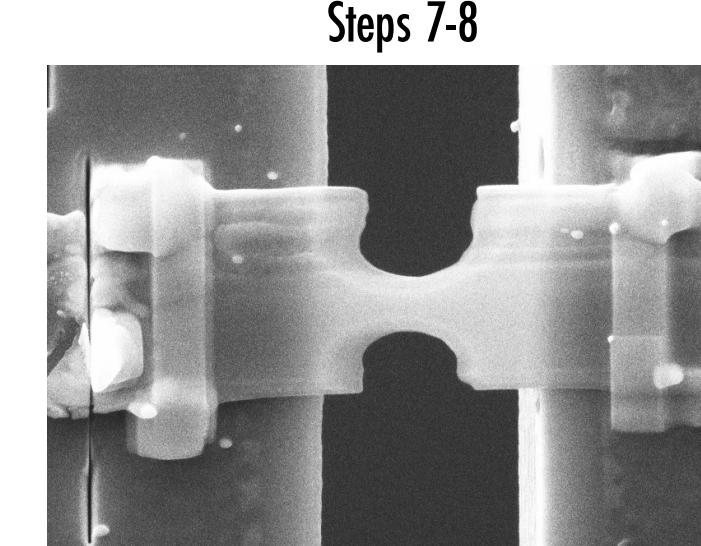
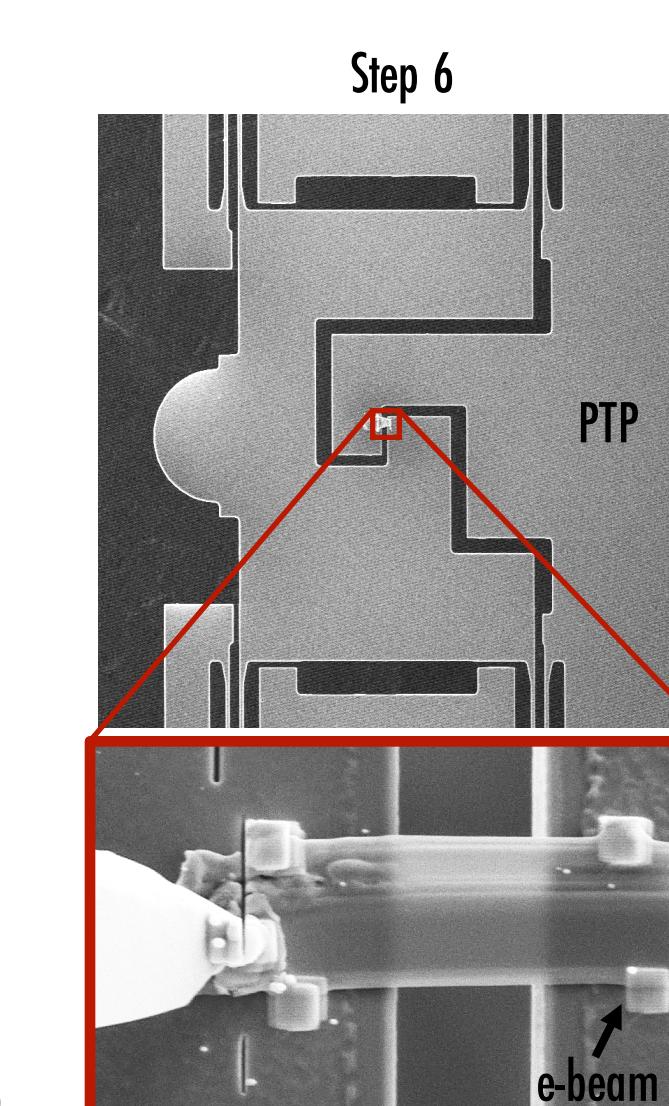
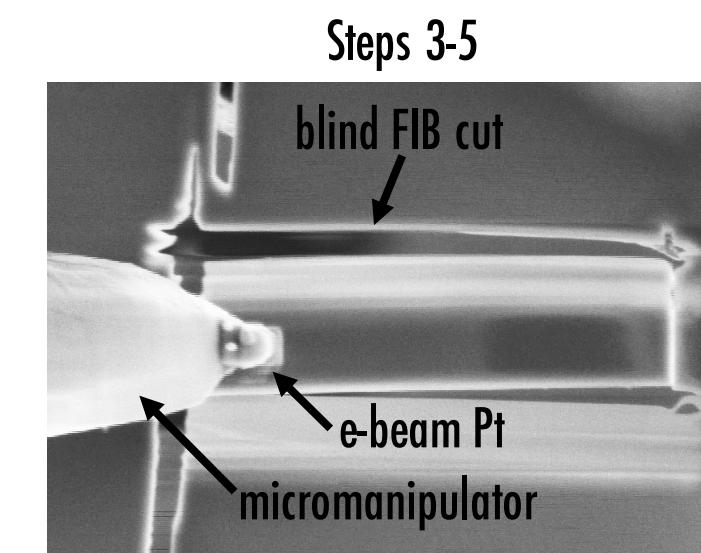
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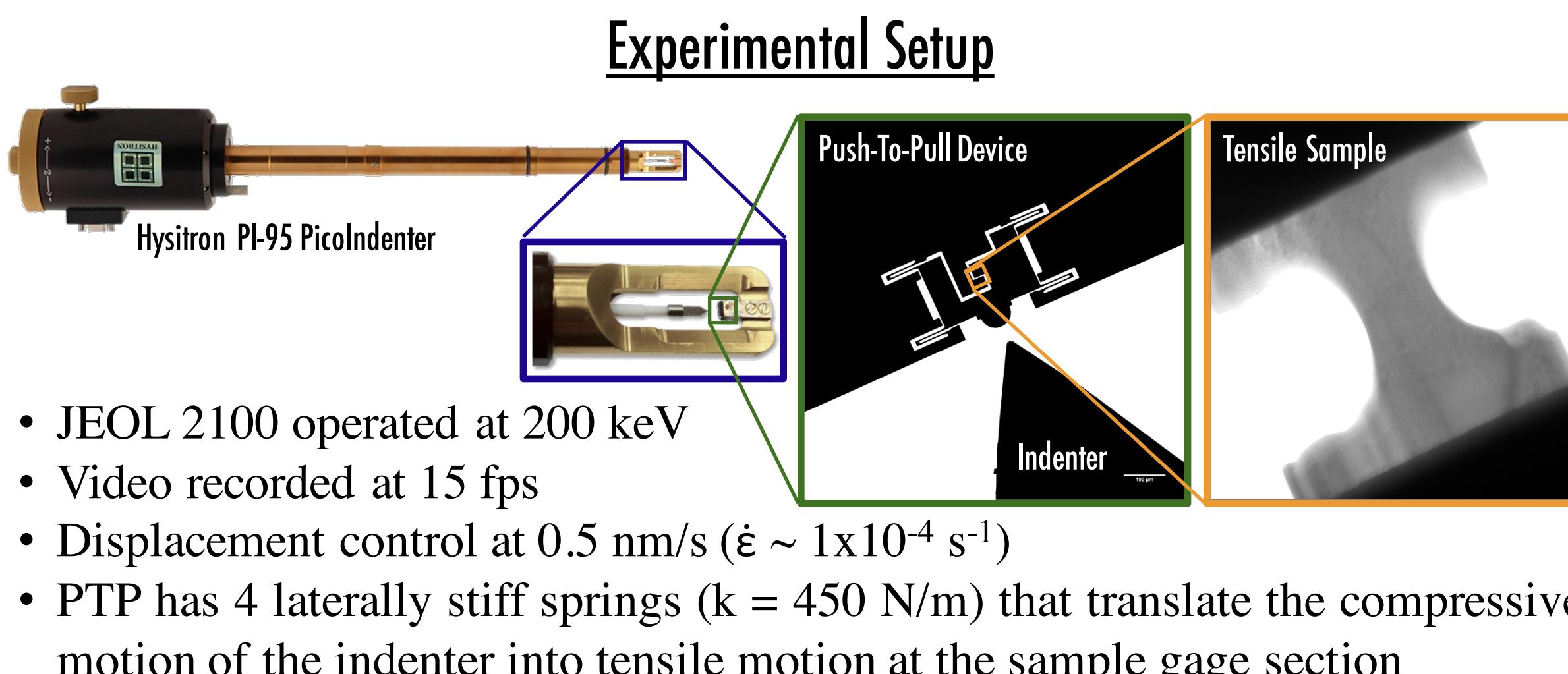
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Nanoscale Sample Preparation

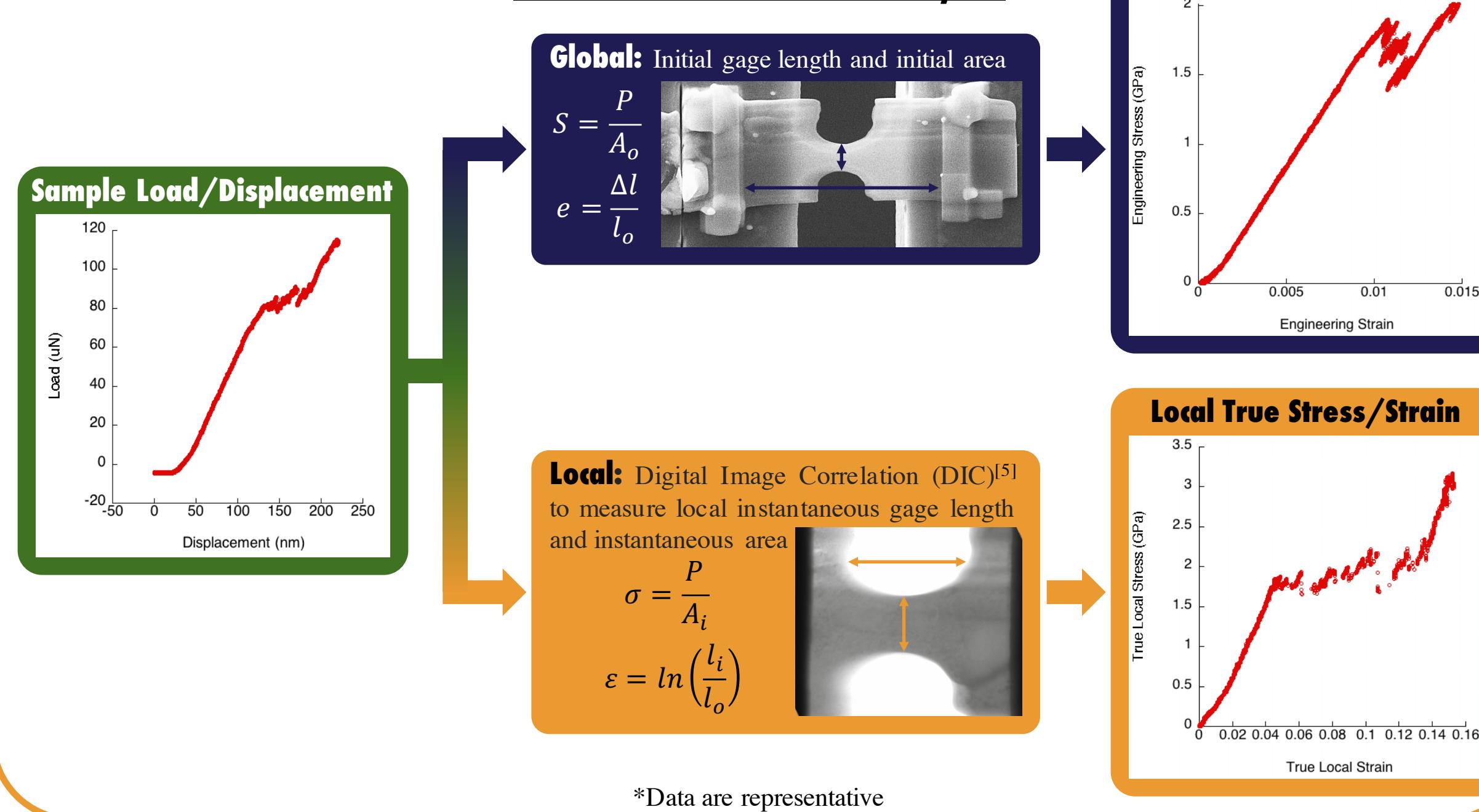
- Exfoliated or ultramicrotomed biotite mica sheet (obtained from Ward's Natural Science Establishment, Bancroft, Ontario, Canada) is floated in DI H₂O onto Cu TEM grid
- Crystallographic orientation determined using TEM diffraction
- In a dual-beam SEM/FIB, 3 blind focused ion beam (FIB) cuts made with Ga⁺ at 30 keV (blind = without imaging with the ion-beam)
- Free end of sample affixed to micromanipulator with e-beam deposited Pt
- Blind FIB cut made to free sample from sheet
- Transferred and affixed to Push-To-Pull (PTP) device with e-beam Pt
- Blind FIB cut made to free sample from micromanipulator
- Blind FIB cuts made to shape tensile sample



Quantitative Mechanical Data Acquisition and Analysis

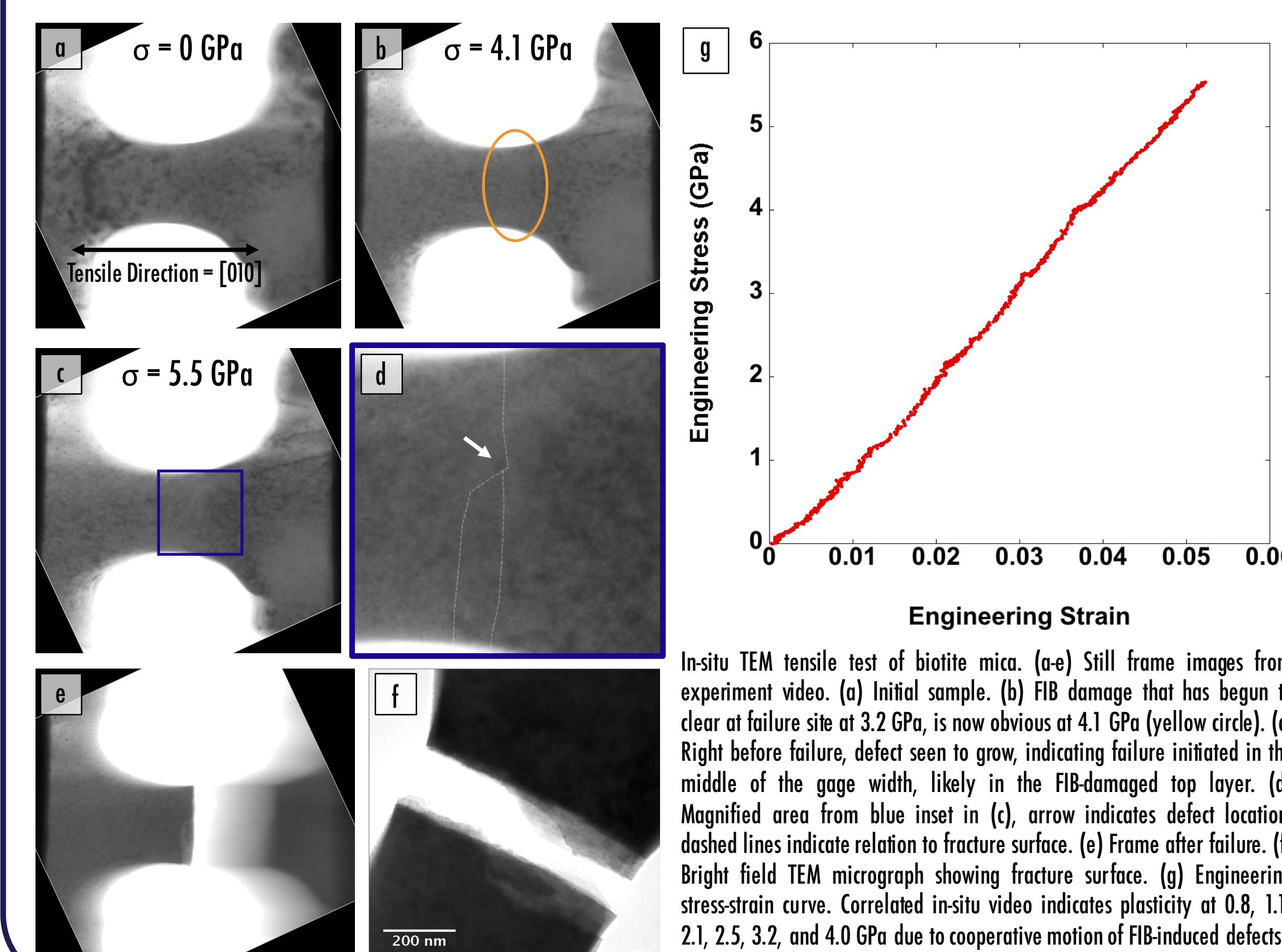


Quantitative Data Analysis



Quantitative In-Situ TEM Tensile Testing of Mica

- Sample
 - 115 nm initial thickness
 - 675 nm initial gage width
 - 1.2 μm initial gage length
 - Tensile loading // to [010](001)
 - Experienced drift during blind FIB cuts that exposed top ~1/4 thickness of gage section to unknown dose of 30 keV Ga⁺ ions
- $E_{[010]\text{meas}} = 110 \text{ GPa}$ ($E_{[010]\text{calc}} = 170 \text{ GPa}$)^[6]
- $\sigma_{\text{max-meas}} = 5.5 \text{ GPa}$ ($\sigma_{\text{max-ideal}} \sim 4-9 \text{ GPa}$)^[7]



Conclusions

- A methodology to quantitatively measure the deformation of constituent geological materials at the nanoscale has been developed.
- A nanoscale biotite mica sample loaded in tension parallel to the basal plane along a multiple-slip direction showed nominally elastic behavior until brittle failure, after reaching near-ideal strength.
- Role of FIB damage unclear and sample drift mitigation techniques will be employed during future sample preparation.
- Slip-oriented ($\tau \neq 0$) samples are expected to yield observable/measurable dislocation activity.

References

- [1] HW Nesbitt and GM Young, *Geochimica et Cosmochimica Acta* **48** (1984), p. 1523–1534.
- [2] RP Wintsch et al, *Journal of Geophysical Research* **100** (1995), p. 13021–13032.
- [3] AK Kronenberg et al, *Journal of Geophysical Research* **95** (1990), p. 19257–19278.
- [4] A Meike, *American Mineralogist* **74** (1989), p. 780–796.
- [5] DIC programed in Matlab by: C. Eberl, R. Thompson, D. Gianola, and S. Bundschuh
- [6] KS Alexandrov and TV Ryzhova, *Bulletin of the Academy of Sciences of the USSR Geophysics Series* **12** (1961), p. 1165–1168.
- [7] A Castellanos-Gomez et al, *Nano Research* **5** (2012), p. 550–557.